



New Insights into X-ray Microscopy and Applications

Guest Editors:

Prof. Dr. Baozhong Mu

MOE Key Laboratory of Advanced
Micro-Structured Materials,
School of Physics Science and
Engineering, Tongji University,
1239 Siping Road, Shanghai
200092, China

Prof. Dr. Feng Wang

Research Center of Laser Fusion,
China Academy of Engineering
Physics, Mianyang 621900, China

Prof. Dr. Shenye Liu

Research Center of Laser Fusion,
China Academy of Engineering
Physics, Mianyang 621900, China

Deadline for manuscript
submissions:

closed (20 November 2023)

Message from the Guest Editors

Dear Colleagues,

X-ray microscopy is a technology that operates in the X-ray band in order to obtain high-resolution imaging of the internal structure of materials, and is widely applied in fields such as biomedicine, materials science, physics, and other disciplines. Compared to visible light, it is difficult to focus X-ray through refraction. Various X-ray modulation techniques, such as grazing incidence, diffraction, phase contrast, and various forms of X-ray microscopy, have been developed. In recent years, light source, X-ray detector, and optical component technology have all made significant progress, thus further improving the application of X-ray microscopy. In the fields of biomedicine, plasma diagnostics, synchrotron radiation and industrial nondestructive testing, these technological advances are particularly evident. X-ray microscopy has become one of the most powerful tools for understanding the internal structure of materials.





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Inspec, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q2 (*Engineering, Multidisciplinary*) / CiteScore - Q1 (*General Engineering*)

Contact Us

Applied Sciences Editorial Office
MDPI, St. Alban-Anlage 66
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](https://twitter.com/Applsci)